

DOCKET NO: 251076US2DIV

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :
YUUICHI HIRANO, ET AL. : ATTN: APPLICATION DIVISION
SERIAL NO: NEW U.S. PCT APPLN. :
(Based on 10/201,921)
FILED: HERewith :
FOR: SEMICONDUCTOR STORAGE :
DEVICE HAVING HIGH SOFT-
ERROR IMMUNITY

PRELIMINARY AMENDMENT

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Prior to examination on the merits, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 6 of this paper.